

Patient-related stressful experiences in psychiatry residency

Hendrickx A, Pattyn T, Sienaert P.

Tijdschrift voor Psychiatrie

2024; 66(3):151-155

ARTICLE IDENTIFIERS

DOI: unavailable

PMID: 38650512

PMCID: not available

JOURNAL IDENTIFIERS

LCCN: not available

pISSN: 0303-7339

eISSN: not available

OCLC ID: 00947250

CONS ID: sn 84005386

US National Library of Medicine ID: 0423731

This article was identified from a query of the SafetyLit database.